TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7MA2574FK

Low-Voltage Octal D-Type Flip-Flop with 3.6 V Tolerant Inputs and Outputs

The TC7MA2574FK is a high performance CMOS octal D-type flip-flop. Designed for use in $1.8~\rm{V},\,2.5~\rm{V}$ or $3.3~\rm{V}$ systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

It is also designed with over voltage tolerant inputs and outputs up to $3.6\ V\!.$

This 8 bit D-type flip-flop is controlled by a clock input (CK) and an output enable input (\overline{OE}). When the \overline{OE} input is high, the eight outputs are in a high impedance state.

The $26~\Omega$ series resistor helps reducing output overshoot and undershoot without external resistor.

All inputs are equipped with protection circuits against static discharge.



- 26Ω series resistors on outputs.
- Low voltage operation: $V_{CC} = 1.8 \sim 3.6 \text{ V}$
- High speed operation: $t_{pd} = 5.1 \text{ ns (max)} (V_{CC} = 3.0 \sim 3.6 \text{ V})$

 $t_{pd} = 6.2 \text{ ns (max) (V}_{CC} = 2.3 \sim 2.7 \text{ V})$

 $t_{pd} = 9.8 \text{ ns (max) (V}_{CC} = 1.8 \text{ V})$

- 3.6 V tolerant inputs and outputs.
- Output current: $I_{OH}/I_{OL} = \pm 12 \text{ mA (min)} (V_{CC} = 3.0 \text{ V})$

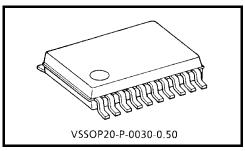
 $I_{OH}/I_{OL} = \pm 8 \text{ mA (min)} (V_{CC} = 2.3 \text{ V})$

 $I_{OH}/I_{OL} = \pm 4 \text{ mA (min) (V}_{CC} = 1.8 \text{ V)}$

- Latch-up performance: -300 mA
- ESD performance: Machine model $\geq \pm 200 \text{ V}$

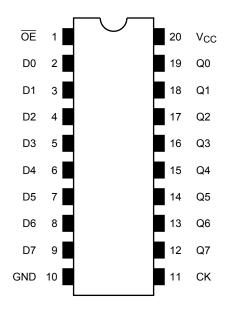
Human body model $\geq \pm 2000 \text{ V}$

- Package: VSSOP (US)
- Power down protection is provided on all inputs and outputs.

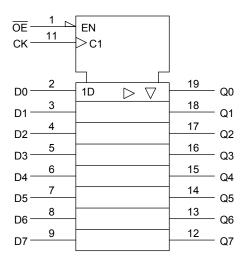


Weight: 0.03 g (typ.)

Pin Assignment (top view)



IEC Logic Level



Truth Table

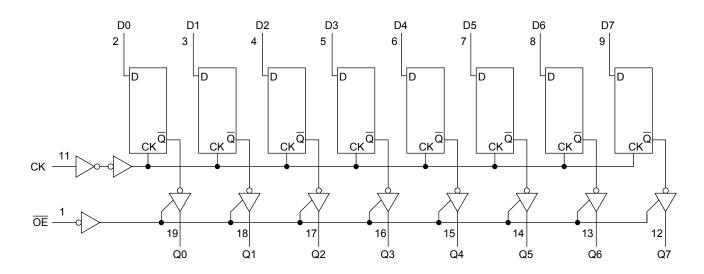
	Inputs					
ŌĒ	CK	D	Outputs			
Н	Х	X	Z			
L		Х	Qn			
L		L	L			
L		Н	Н			

X: Don't care

Z: High impedance

Q_n: No change

System Diagram



Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	-0.5~4.6	V
DC input voltage	V _{IN}	-0.5~4.6	V
DC output voltage	V _{OUT}	-0.5~4.6 (Note 2)	V
DC output voltage	VOUI	-0.5~V _{CC} + 0.5 (Note 3)	v
Input diode current	I _{IK}	-50	mA
Output diode current	I _{OK}	±50 (Note 4)	mA
DC output current	lout	±50	mA
Power dissipation	P _D	180	mW
DC V _{CC} /ground current	I _{CC} /I _{GND}	±100	mA
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Off-state

Note 3: High or low state. IOUT absolute maximum rating must be observed.

Note 4: Vout < GND, Vout > Vcc

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	1.8~3.6	V	
Supply voltage	vcc	1.2~3.6 (Note 2)	v	
Input voltage	V _{IN}	-0.3~3.6	V	
Output voltage	V	0~3.6 (Note 3)	V	
Output voltage	V _{OUT}	0~V _{CC} (Note 4)	V	
		±12 (Note 5)		
Output current	I _{OH} /I _{OL}	±8 (Note 6)	mA	
		±4 (Note 7)		
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~10 (Note 8)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

3

Note 2: Data retention only

Note 3: Off-state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \sim 3.6 \text{ V}$

Note 6: $V_{CC} = 2.3 \sim 2.7 \text{ V}$

Note 7: $V_{CC} = 1.8 \text{ V}$

Note 8: $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$



Electrical Characteristics

DC Characteristics (Ta = $-40~85^{\circ}$ C, 2.7 V < V_{CC} \leq 3.6 V)

Characteri	stics	Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
	High level	V _{IH}			2.7~3.6	2.0	_	
Input voltage	Low level	V _{IL}			2.7~3.6		0.8	V
				I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	_	
	High level	VoH	V _{IN} = V _{IH} or V _{II}	I _{OH} = -6 mA	2.7	2.2	_	
		011		I _{OH} = -8 mA	3.0	2.4	_	
Output voltage				I _{OH} = -12 mA	3.0	2.2	_	V
		nyol V-	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 100 μA	2.7~3.6	_	0.2	
	Low level			I _{OL} = 6 mA	2.7	_	0.4	
	Low level	V _{OL}		I _{OL} = 8 mA	3.0	_	0.55	
				I _{OL} = 12 mA	3.0	_	0.8	
Input leakage curre	nt	I _{IN}	V _{IN} = 0~3.6 V		2.7~3.6	_	±5.0	μΑ
3-state output off-state current I _{OZ}		$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = 0~3.6 \text{ V}$		2.7~3.6	_	±10.0	μА	
Power off leakage of	urrent	l _{OFF}	V _{IN} , V _{OUT} = 0~3.6 V		0	_	10.0	μΑ
		laa	V _{IN} = V _{CC} or GND		2.7~3.6	_	20.0	
Quiescent supply co	urrent	Icc	$V_{CC} \le (V_{IN}, V_{OUT}) \le 3$.6 V	2.7~3.6	_	±20.0	μΑ
		Δlcc	$V_{IH} = V_{CC} - 0.6 V$ (per	input)	2.7~3.6	_	750	

DC Characteristics (Ta = $-40~85^{\circ}$ C, 2.3 V \leq V_{CC} \leq 2.7 V)

Character	ristics	Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit		
Innut voltage	High level	V _{IH}		_	2.3~2.7	1.6	_	V		
Input voltage	Low level	V _{IL}		_	2.3~2.7	_	0.7	V		
				I _{OH} = -100 μA	2.3~2.7	V _{CC} - 0.2	_			
	High level	VoH	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -4 mA	2.3	2.0	_			
						I _{OH} = -6 mA	2.3	1.8	_	
Output voltage				$I_{OH} = -8 \text{ mA}$	2.3	1.7	_	V		
				$I_{OL} = 100 \mu A$	2.3~2.7	_	0.2			
	Low level	V _{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$V_{IN} = V_{IH} \ or \ V_{IL}$	I _{OL} = 6 mA	2.3	_	0.4		
					I _{OL} = 8 mA	2.3	_	0.6		
Input leakage curre	ent	I _{IN}	V _{IN} = 0~3.6 V		2.3~2.7	_	±5.0	μА		
3-state output off-state current		1	V _{IN} = V _{IH} or V _{IL}	$V_{IN} = V_{IH}$ or V_{IL}			±10.0			
		loz	V _{OUT} = 0~3.6 V		2.3~2.7	_	±10.0	μА		
Power off leakage	current	loff	V _{IN} , V _{OUT} = 0~3.6 V		0	_	10.0	μА		
Out and a second second		loo	V _{IN} = V _{CC} or GND		2.3~2.7	_	20.0			
Quiescent supply of	Juitelli	Icc	$V_{CC} \le (V_{IN}, V_{OUT}) \le$	3.6 V	2.3~2.7	_	±20.0	μА		

DC Characteristics (Ta = $-40\sim85^{\circ}$ C, 1.8 V \leq V_{CC} < 2.3 V)

Characteris	stics	Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
lanut voltage	High level	V _{IH}		_	1.8~2.3	0.7 × V _{CC}	_	V
Input voltage	Low level	V _{IL}		_	1.8~2.3	_	0.2 × V _{CC}	V
	High level	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -100 μA	1.8	V _{CC} - 0.2	_	
Output voltage				I _{OH} = -4 mA	1.8	1.4		V
	Low level	\\\-\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	$I_{OL} = 100 \mu A$	1.8		0.2		
	LOW level	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 4 mA	1.8		0.3	
Input leakage currer	nt	I _{IN}	V _{IN} = 0~3.6 V		1.8		±5.0	μΑ
3-state output off-sta	output off-state current I_{OZ} $V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \sim 3.6 \text{ V}$		1.8		±10.0	μА		
Power off leakage c	urrent	l _{OFF}	V _{IN} , V _{OUT} = 0~3.6 V		0		10.0	μА
Quicecent augusty a			V _{IN} = V _{CC} or GND	V _{IN} = V _{CC} or GND		_	20.0	
Quiescent supply cu	irrent	Icc	$V_{CC} \le (V_{IN}, V_{OUT}) \le 3.6 \text{ V}$		1.8	_	±20.0	μА

5 2007-10-19

AC Characteristics (Ta = -40~85°C, Input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500~\Omega$)

Characteristics	Symbol	rmbol Test Condition		Min	Max	Unit
Characteristics	Syllibol	rest Condition	V _{CC} (V)	IVIIII	IVIAX	Offic
			1.8	100	_	
Maximum clock frequency	f _{max}	Figure 1, Figure 2	2.5 ± 0.2	200	_	MHz
			3.3 ± 0.3	250		
	4		1.8	1.5	9.8	
Propagation delay time (CK-Q)	t _{pLH}	Figure 1, Figure 2	2.5 ± 0.2	8.0	6.2	ns
	t _{pHL}		3.3 ± 0.3	0.6	5.1	
	4		1.8	1.5	9.8	
3-state output enable time	t _{pZL}	Figure 1, Figure 3	2.5 ± 0.2	8.0	6.5	ns
	t _{pZH}		3.3 ± 0.3	0.6	5.0	
	t _{pLZ}	Figure 1, Figure 3	1.8	1.5	7.7	ns
3-state output disable time			2.5 ± 0.2	8.0	4.3	
			3.3 ± 0.3	0.6	3.9	
		Figure 1, Figure 2	1.8	4.0		
Minimum pulse width (CK)	t _{w (H)}		2.5 ± 0.2	1.5		ns
	t _{w (L)}		3.3 ± 0.3	1.5		
			1.8	2.5		
Minimum set-up time	ts	Figure 1, Figure 2	2.5 ± 0.2	1.5		ns
			3.3 ± 0.3	1.5		
			1.8	1.0		
Minimum hold time	th	Figure 1, Figure 2	2.5 ± 0.2	1.0	_	ns
			3.3 ± 0.3	1.0	_	
	4		1.8	_	0.5	
Output to output skew	t _{osLH}	(Note)	2.5 ± 0.2	_	0.5	ns
	t _{osHL}		3.3 ± 0.3	_	0.5	

For $C_L = 50\ pF$, add approximately 300 ps to the AC maximum specification.

Note: This parameter is guaranteed by design.

 $(t_{\text{OSLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|, \, t_{\text{OSHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|)$

6 2007-10-19

Dynamic Switching Characteristics (Ta = 25°C, Input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF)

Characteristics	Symbol	Test Condition	V	/cc (V)	Тур.	Unit
		V _{IH} = 1.8 V, V _{IL} = 0 V (No	te)	1.8	0.15	
Quiet output maximum dynamic V _{OL}	V _{OLP}	V _{IH} = 2.5 V, V _{IL} = 0 V (No	te)	2.5	0.25	V
		V _{IH} = 3.3 V, V _{IL} = 0 V (No	te)	3.3	0.35	
	V _{OLV}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (No.	te)	1.8	-0.15	V
Quiet output minimum dynamic V_{OL}		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (No.	te)	2.5	-0.25	
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (No.	te)	3.3	-0.35	
	V _{OHV}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (No.	te)	1.8	1.55	
Quiet output minimum dynamic V _{OH}		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (No.	te)	2.5	2.05	V
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (No.	te)	3.3	2.65	

Note: This parameter is guaranteed by design.

Capacitive Characteristics (Ta = 25°C)

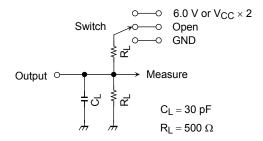
Characteristics	Symbol	Test Condition			Tun	Unit
Characteristics	Syllibol			V _{CC} (V)	Тур.	Offic
Input capacitance	C _{IN}	_		1.8, 2.5, 3.3	6	pF
Output capacitance	C _{OUT}	_		1.8, 2.5, 3.3	7	pF
Power dissipation capacitance	C _{PD}	$f_{IN} = 10 \text{ MHz}$	(Note)	1.8, 2.5, 3.3	20	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$

AC Test Circuit



Parameter	Switch		
t _{pLH} , t _{pHL}	Open		
t _{pLZ} , t _{pZL}	6.0 V V _{CC} × 2	$@V_{CC} = 3.3 \pm 0.3 \text{ V} \\ @V_{CC} = 2.5 \pm 0.2 \text{ V} \\ @V_{CC} = 1.8 \text{ V}$	
t _{pHZ} , t _{pZH}	GND		

Figure 1

AC Waveform

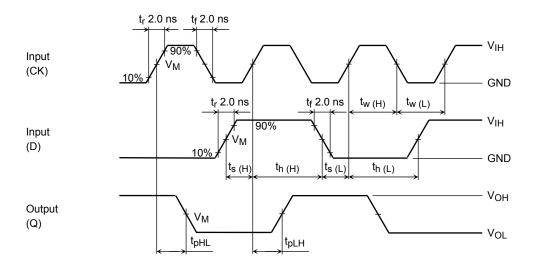


Figure 2 $t_{pLH}, t_{pHL}, t_w, t_s, t_h$

8

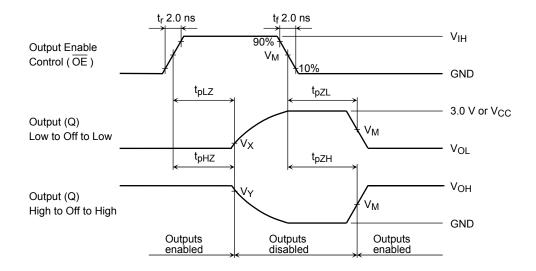
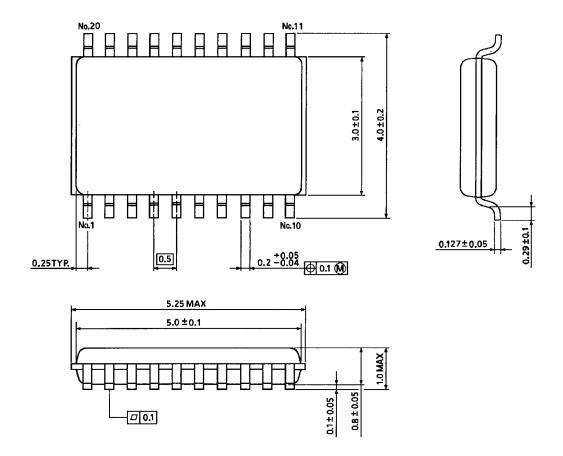


Figure 3 $t_{\text{pLZ}},\,t_{\text{pHZ}},\,t_{\text{pZL}},\,t_{\text{pZH}}$

Cumbal		V_{CC}	
Symbol	$3.3\pm0.3~\textrm{V}$	2.5 ± 0.2 V	1.8 V
V _{IH}	2.7 V	V _{CC}	V _{CC}
V_{M}	1.5 V	V _{CC} /2	V _{CC} /2
VX	V _{OL} + 0.3 V	V _{OL} + 0.15 V	V _{OL} + 0.15 V
V_{Y}	V _{OH} – 0.3 V	V _{OH} – 0.15 V	V _{OH} – 0.15 V

9 2007-10-19

Package Dimensions



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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